

EXHIBITOR REGISTRATION FORM

ASTR 2007 Workshop on Accelerated Stress Testing & Reliability October 31 – November 2, 2007

Hotel:

Greenbelt Marriott. 6400 Ivy Lane, Greenbelt MD 20700. Ph# 301-441-3700. www.marriott.com

Hosted By:

IEEE/CPMT TC-ASTR and Technically co-sponsored by **UC Santa Cruz**

Workshop Overview:

Over the last few years, Accelerated Stress Testing (AST) has been embraced by an ever widening array of worldwide companies seeking to reconcile the need for the highest quality product with the necessary push for early time-to-market. The purpose of the AST Workshop is to share ideas on better ways of accelerating and detecting hidden defects, flaws, and weaknesses in electronic and electro-mechanical hardware that would result in failures during usage. These techniques are focused on testing electronic hardware to destruction limits and root cause investigation to determine the physics-of-failure. The goal of AST is to produce mature products at market introduction and, in making it robust, the product can be screened for manufacturing defects with high combined stresses (beyond end-use specifications) for shorter lengths of time.

See: <http://www.ewh.ieee.org/soc/cpmt/tc7/ast2007/> , for additional AST Workshop Information.

Topics:

Advanced Approaches to AST
Reliability Improvement Techniques
AST Data Collection
Advanced Data Analysis
Failure Analysis Techniques
Reliability Simulation and Modeling
Physics of Failure Techniques
Stress Screening Techniques
AST Case Studies

Stress Selection Amplitudes and Profiles
Functional Test During Stress Testing
AST Results on New Technologies
ESD
AST on hardware/software interactions
AST impact on Business and Engineering Decisions
Equipment and Facility considerations
Vibration Selection

Tutorials:

The all day tutorial program will be held on the first day of the Workshop and features well respected experts sharing their experiences and hard learned lessons. Two parallel sessions, Basic AST and Advanced AST Subjects, will ensure that experienced practitioners as well as those who are just entering the field will find useful and interesting presentations.

Registration:

Please complete the form below and return with payment to the address specified.

For more information, visit:

ASTR 2007 -- <http://www.ewh.ieee.org/soc/cpmt/tc7/ast2007>

CMPT TC-ASTR -- <http://www.ewh.ieee.org/soc/cpmt/tc7>

IEEE Reliability Society -- <http://www.ewh.ieee.org/soc/rs>

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Exhibitor Space (~10'x10'), one CD rom of proceedings, two attendee passes	\$ 1250.00
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